

Notice of References Cited		Application/Control No. 10/560,001	Applicant(s)/Patent Under Reexamination TOMOZAWA ET AL.	
		Examiner ALEXANDER C. WITKOWSKI	Art Unit 2853	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,494,567 B2	12-2002	Murai, Masami	347/71
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*	F	US-7,083,269 B2	08-2006	Murai, Masami	347/68
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	Sumi et al.: Thin Solid Films, Vol.315, Issues 1-2, March 1998, pp.77-85: Effect of the annealing temperature on structural and piezoelectric properties of the sol-gel Pb(Zr 0.56Ti 0.44) 0.90 (Mg 1/3 Nb 2/3) 0.10 O3 films
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.